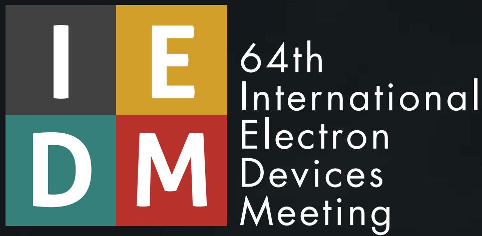

2018 IEDM Conference Theme

Device Breakthroughs from Quantum to 5G and Beyond

2018 IEEE International Electron Devices Meeting

December 1st - 5th, 2018

Hilton San Francisco Union Square
San Francisco, California

Focused Call for Papers

IEDM is pleased to announce increased technical focus in the area of:

Characterization, Reliability & Yield

Topics

Papers are solicited in the following themes of interest:

- Transistor degradation due to BTI, hot carriers
- Soft-errors in logic and memory as well as error correction
- ESD and latch-up mechanisms
- Time dependent breakdown of dielectrics (FEOL/MEOL/BEOL)
- Interconnect and contact degradation (MEOL/BEOL)

New or trending areas include:

- III-V power management
- Resistive devices
- Emerging memories

Streamlined Paper Submission

Submission deadline: August 1st

Single submission of final, four-page paper

For More Information

IEDM Online: ieee-iedm.org
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